

FORM PTO-1449

INFORMATION DISCLOSURE STATEMENT

ATTY. DOCKET NO. 1875.0220000

APPLICATION NO. 09/739,752

APPLICANT: CHEN et al.

FILING DATE: December 20, 2000

GROUP: 2811



U.S. PATENT DOCUMENTS

INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA1						
	AB1						
	AC1						
	AD1						
	AE1						
	AF1						

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
	AG1						Yes No
	AH1						Yes No
	AI1						Yes No

OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

	AJ	1	
	AK	1	Schroder, Dieter K., "Semiconductor Material and Device Characterization", Fig. E6.5(a), Oxide failure modes, John Wiley & Sons, Inc., 2 nd Edition, p391, (1998)
	AL	1	Schroder, Dieter K., "Semiconductor Material and Device Characterization", Fig. 6.40, Charge-to-breakdown as a function of oxide thickness, John Wiley & Sons, Inc., 2 nd Edition, p397, (1998)

EXAMINER

DATE CONSIDERED

8/30/02

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.